

## **ULTRAFAST SOFT RECOVERY RECTIFIER DIODE**

### **PRODUCT APPLICATIONS**

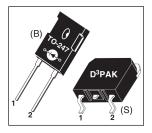
- Anti-Parallel Diode
  - -Switchmode Power Supply
  - -Inverters
- Free Wheeling Diode
  - -Motor Controllers
  - -Converters
  - -Inverters
- Snubber Diode
- PFC

#### **PRODUCT FEATURES**

- Ultrafast Recovery Times
- Soft Recovery Characteristics
- Popular TO-247 Package or Surface Mount D<sup>3</sup>PAK Package
- Low Forward Voltage
- Low Leakage Current

#### **PRODUCT BENEFITS**

- Low Losses
- · Low Noise Switching
- Cooler Operation
- . Higher Reliability Systems
- Increased System Power Density





- 1 Cathode
- 2 Anode Back of Case - Cathode

#### **MAXIMUM RATINGS**

All Ratings:  $T_C = 25^{\circ}C$  unless otherwise specified.

Symbol	Characteristic / Test Conditions	APT60D100(B/S)G	UNIT
V <sub>R</sub>	Maximum D.C. Reverse Voltage		
V <sub>RRM</sub>	Maximum Peak Repetitive Reverse Voltage	1000	Volts
V <sub>RWM</sub>	Maximum Working Peak Reverse Voltage		
I <sub>F(AV)</sub>	Maximum Average Forward Current (T <sub>C</sub> = 142°C, Duty Cycle = 0.5)	60	
I <sub>F(AV)</sub>	RMS Forward Current (Square wave, 50% duty)	152	Amps
I <sub>FSM</sub>	Non-Repetitive Forward Surge Current (T <sub>J</sub> = 45°C, 8.3ms)	540	
T <sub>J</sub> ,T <sub>STG</sub>	Operating and StorageTemperature Range	-55 to 175	°C
T <sub>L</sub>	Lead Temperature for 10 Sec.	300	

## STATIC ELECTRICAL CHARACTERISTICS

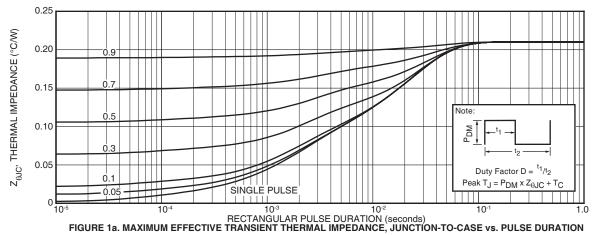
Symbol	Characteristic / Test Conditions		MIN	TYP	MAX	UNIT
V <sub>F</sub>	Forward Voltage	I <sub>F</sub> = 60A		1.9	2.5	Volts
		I <sub>F</sub> = 120A		2.2		
		I <sub>F</sub> = 60A, T <sub>J</sub> = 125°C		1.7		
I <sub>RM</sub>	Maximum Reverse Leakage Current	V <sub>R</sub> = V <sub>R</sub> Rated			250	μΑ
		$V_R = V_R$ Rated, $T_J = 125$ °C			500	
C <sub>T</sub>	Junction Capacitance, V <sub>R</sub> = 200V			65		pF

Symbol	Characteristic	Test Conditions	MIN	TYP	MAX	UNIT
t <sub>rr</sub>	Reverse Recovery Time $I_F = 1A$ , $di_F/dt =$	$-100A/\mu s$ , $V_R = 30V$ , $T_J = 25^{\circ}C$	-	34		ns
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 60A$ , $di_F/dt = -200A/\mu s$ $V_R = 667V$ , $T_C = 25^{\circ}C$	1	280		115
Q <sub>rr</sub>	Reverse Recovery Charge		-	760		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	6	-	Amps
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 60A$ , $di_F/dt = -200A/\mu s$ $V_R = 667V$ , $T_C = 125°C$	-	350		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	3600		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	16	-	Amps
t <sub>rr</sub>	Reverse Recovery Time	$I_F = 60A$ , $di_F/dt = -1000A/\mu s$ $V_R = 667V$ , $T_C = 125°C$	-	170		ns
Q <sub>rr</sub>	Reverse Recovery Charge		-	5650		nC
I <sub>RRM</sub>	Maximum Reverse Recovery Current		-	50		Amps

#### THERMAL AND MECHANICAL CHARACTERISTICS

Symbol	Characteristic / Test Conditions	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Junction-to-Case Thermal Resistance			.21	°C/W
$R_{ heta JA}$	Junction-to-Ambient Thermal Resistance			40	
W <sub>T</sub>	Package Weight		0.22		oz
			5.9		g
Torque	Maximum Mounting Torque			10	lb•in
				1.1	N•m

APT Reserves the right to change, without notice, the specifications and information contained herein.



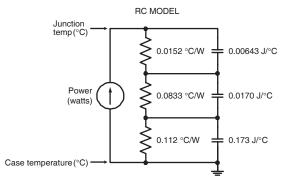
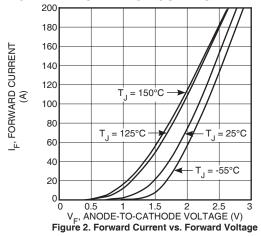


FIGURE 1b, TRANSIENT THERMAL IMPEDANCE MODEL



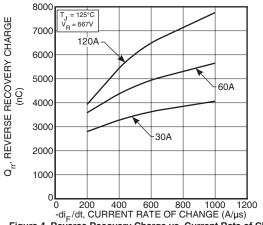
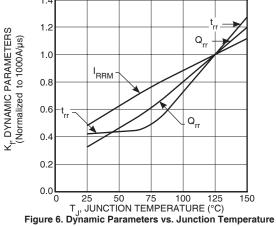
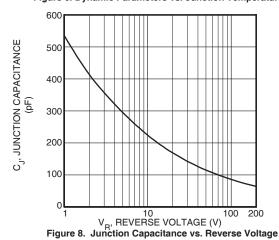


Figure 4. Reverse Recovery Charge vs. Current Rate of Change





500  $t_{\rm rr}$ , REVERSE RECOVERY TIME (ns) 120Å 400 60A 300 30A 200 100 0 200 400 600 800 1000 12 -di<sub>F</sub>/dt, CURRENT RATE OF CHANGE(A/µs) 1000 1200

Figure 3. Reverse Recovery Time vs. Current Rate of Change

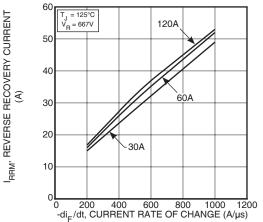


Figure 5. Reverse Recovery Current vs. Current Rate of Change

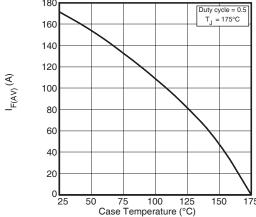


Figure 7. Maximum Average Forward Current vs. CaseTemperature

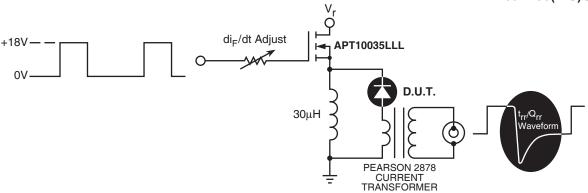


Figure 9. Diode Test Circuit

Zero

- 1 I<sub>F</sub> Forward Conduction Current
- 2 di<sub>E</sub>/dt Rate of Diode Current Change Through Zero Crossing.
- 3 I<sub>RRM</sub> Maximum Reverse Recovery Current.
- 4 t<sub>rr</sub> Reverse Recovery Time, measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I<sub>RRM</sub> and 0.25•I<sub>RRM</sub> passes through zero.
- $\mathbf{5}$   $Q_{rr}$  Area Under the Curve Defined by  $I_{RRM}$  and  $t_{rr}$ .

Figure 10, Diode Reverse Recovery Waveform and Definitions

## TO-247 Package Outline

#### 4.69 (185) 5.31 (209) 1.49 (098) 6.15 (.242) BSC 20.80 (819) 21.46 (.845) 20.80 (.819) 21.46 (.845) 3.50 (.138) 3.81 (.150) 4.50 (.177) Max. 1.65 (.065) 1.016 (.040) 1.016 (.040) 2.21 (.087) 2.59 (.102) Dimensions in Millimeters and (Inches)

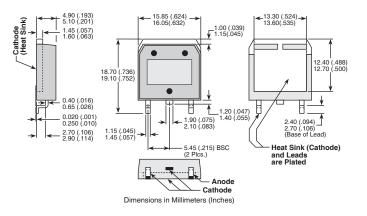
## D<sup>3</sup>PAK Package Outline

5

0.25 I<sub>RRM</sub>

@3 100% Sn

2





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